TOSHIBA CMOS Digital Integrated Circuits Silicon Monolithic

TC9WMA1FK

1,024-Bit (128 × 8 Bit) Serial E²PROM

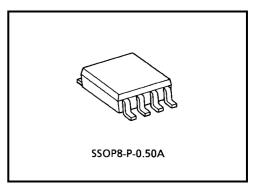
The TC9WMA1FK is electrically erasable/programmable nonvolatile memory (${\rm E^2PROM}$).

Features

- Serial data input/output
- Programmable in units of one word and collectively erasable in one operation
- Automatically set programming time (built-in timer)
- Programming time: $10 \text{ ms} \text{ (max)} \text{ (V}_{CC} = 3.0 \text{ to } 3.6 \text{ V)}$

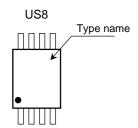
13 ms (max) ($V_{CC} = 2.7 \text{ to } 3.6 \text{ V}$)

- Overwriting enabled or disabled by software
- Single power supply and low power consumption
- Operating power supply voltage (2.7 to 3.6 V)
- Wide operating temperature range (-40 to 85°C)

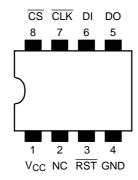


Weight: 0.01 g (typ.)

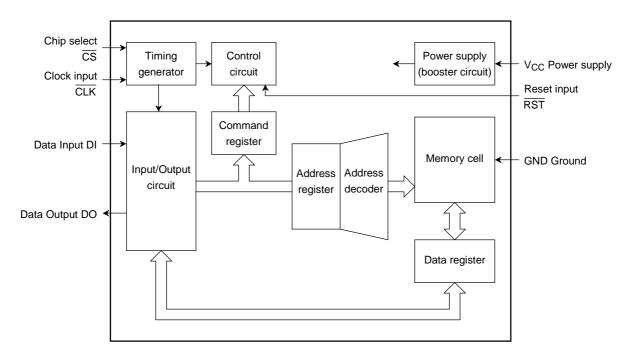
Product Marking



Pin Assignment (top view)



Block Diagram



Pin Function

Pin Name	Input/Output	Function
cs	Input	Chip select A low on CS selects the chip. Always return CS high temporarily before executing instructions.
CLK	Input	Clock input The data on DI is latched by a rising edge of CLK. Data is output to DO by a falling edge of CLK. CLK is effective when CS is low.
DI	Input	Serial data input This pin is used to enter addresses, commands, and data into the chip.
DO	Output	Serial data output This pin outputs data from the chip.
RST	Input	Reset input A low on this input resets the chip.
NC	_	No connection (not connected internally)
Vcc	Power supply	2.7 V~3.6 V
GND	i ower suppry	0 V (GND)

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Functional Description

1. Types of Instructions

Onesetten	A 1.1		Command						D-1-	
Operation	Address	C0	C1	C2	C3					Data
Read	A0~A6, 0	1	0	0	0	0	0	0	0	
Program	A0~A6, 0	0	1	1	0	0	0	0	0	D0~D7
All erase	******	0	0	1	1	0	0	0	0	
Busy monitor	******	1	0	1	1	0	0	0	0	
Overwrite enable	******	1	0	0	1	0	0	0	0	
Overwrite disable	******	1	1	0	1	0	0	0	0	

^{*:} Don't care

2. Operation Method

Be sure to return \overline{CS} and \overline{CLK} high temporarily before entering instructions.

After $\overline{\text{CS}}$ is asserted low, $\overline{\text{CLK}}$ becomes effective, acting as a serial transfer synchronizing signal. The data on DI is latched by a rising edge of $\overline{\text{CLK}}$, while data is output to DO by a falling edge of $\overline{\text{CLK}}$. Instructions can only be executed when the chip is not being programmed or collectively erased (i.e., when the ready/busy status signal is high). However, the Busy Monitor instruction can be entered at any time. Only the commands listed in the above table can be used. Do not use any other command.

(1) Read

When the Read instruction is entered, memory data at the specified address is read out and is serially output from the DO pin.

(2) Program

When the Program instruction is entered, overwrite operation automatically starts internally in the chip, and memory data at the specified address is overwritten with the input data. After the instruction is entered, $\overline{\text{CS}}$ can be returned high even while overwrite operation is in progress internally.

(3) All Erase

When the All Erase instruction is entered, erase operation automatically starts internally in the chip, and memory data at all addresses are erased. After the instruction is entered, $\overline{\text{CS}}$ can be returned high even while erase operation is in progress internally. Execution of this command clears the memory data to 0.

(4) Busy Monitor

When the Busy Monitor instruction is entered, a ready/busy status signal is output from the DO pin. This output signal is low while the chip is being programmed or collectively erased, and is high after programming or collective erase operation is completed.

The ready/busy status signal is output continuously until $\overline{\text{CS}}$ is returned high.

(5) Overwrite Enable/Disable

When the Overwrite Enable instruction is entered, the chip is placed in overwrite enable mode, where the Program and All Erase instructions are enabled. When the Overwrite Disable instruction is entered, the chip is placed in overwrite disable mode, where the Program and All Erase instructions both are disabled.

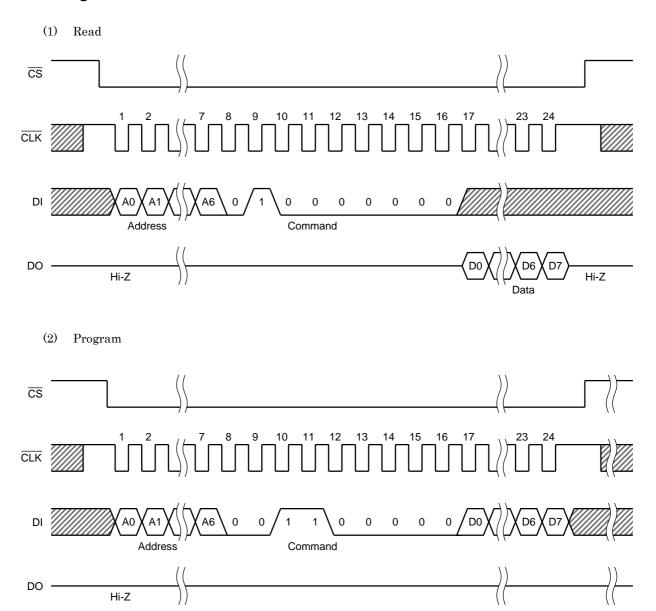
Once the chip is placed in overwrite disable mode, it remains disabled against overwriting unless the Overwrite Enable instruction is entered.

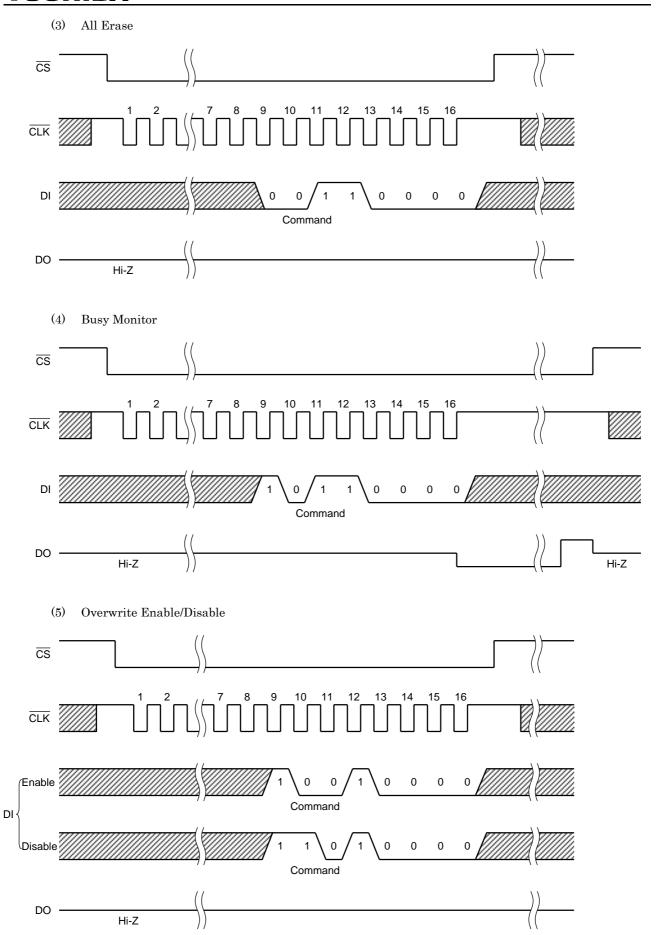
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3. Precautions to be Taken at Power ON/OFF

- (1) A wait time of 1 ms is required before the chip starts operation after it is powered on.
- (2) RST must be pulled low when the power to the chip turns ON or OFF.
- (3) The chip is placed in overwrite disable mode by reset.

4. Timing Chart





Maximum Ratings (GND = 0 V)

Characteristics	Symbol	Rating	Unit
Power supply voltage	V _{CC}	-0.3~4.6	V
Input voltage	V _{IN}	$-0.3 \sim V_{CC} + 0.3$	V
Output voltage	V _{OUT}	$-0.3 \sim V_{CC} + 0.3$	V
Power dissipation	P _D	200 (25°C)	mW
Soldering temperature (in time)	T _{sld}	260 (10 s)	°C
Storage temperature	T _{stg}	-55~125	°C
Operating temperature	T _{opr}	-40~85	°C

Recommended Operating Conditions (GND = 0 V, $T_{opr} = -40 \sim 85$ °C)

Characteristics	Symbol	Test Condition	Min	Max	Unit
Power supply voltage	V _{CC}		2.7	3.6	V

Recommended Operating Conditions (GND = 0 V, V_{CC} = 2.7~3.6 V, T_{opr} = -40~85°C)

Characteristics	Symbol	Pin	Test Condition	Min	Max	Unit
Low level input voltage	V_{IL}		V _{CC} = 2.7 V	0	0.45	V
High level input voltage	V _{IH1}	CS , DI, RST	V _{CC} = 3.6 V	1.6	V _{CC}	V
riigirievei iriput voltage	V _{IH2}	CLK	V _{CC} = 3.6 V	2.2	V _{CC}	V
Operating frequency	f _{CLK}			0	1	MHz

Electrical Characteristics

D.C. Characteristics (GND = 0 V, $V_{CC} = 2.7 \sim 3.6 \text{ V}$, $T_{opr} = -40 \sim 85 ^{\circ}\text{C}$)

Characteristics	Symbol	Test Condition	Min	Тур.	Max	Unit
Input current	IЦ		_	_	±5	μА
Output leakage current	I _{LO}		_	_	±5	μА
High level output voltage	V _{OH}	$V_{CC} = 2.7 \text{ V}, I_{OH} = -1 \text{ mA}$	V _{CC} - 0.4	_	_	V
Low level output voltage	V _{OL}	$V_{CC} = 2.7 \text{ V}, I_{OL} = 2 \text{ mA}$	_	_	0.4	V
Quiescent supply current	I _{CC1} (Note1)		_	_	5	μΑ
Supply current during read	I _{CC2} (Note2)		_	_	1.5	mA
Supply current during all erase/program	I _{CC3} (Note3)				1.0	mA

Note 1: $\overline{CS} = 1$ (except when busy, however)

Note 2: Current that flows for a period from a fall of the 14th to a fall of the 17th $\overline{\text{CLK}}$ pulse when executing the read instruction.

Note 3: Current that flows while executing the all erase or program instruction.

A.C. Characteristics (GND = 0 V, V_{CC} = 2.7~3.6 V, T_{opr} = -40~85°C)

Characteristics	Symbol	Test Condition	Min	Max	Unit
Maximum clock frequency	f _{MAX}		0	1	MHz
Minimum clock pulse width	twCLK (L)		400		no
Millimum clock puise width	twCLK (H)		400	_	ns
Minimum reset pulse width	t _{WRST}		1	_	μS
Minimum chip select pulse width	t _{WCS}		1	_	μS
Reset setup time	t _{RSS}	RST setup time when CS is switched over	1	_	μS
Clock setup time	tcks	CLK setup time when CS is switched over	250	_	ns
CS setup time	tcss	CS setup time when CLK is switched over	250	_	ns
	t _{pLH}				
	t_{pHL}	Time from CLK switchover until valid	_	250	
Propagation delay time (Note4)	t _{pZH}	data is output		200	ns
(Note 1)	t_{pZL}				110
	t_{pLZ}	Time from CS switchover until output	_	500	
	t_{pHZ}	data goes Hi-Z		000	
Input data setup time	t _S	Input data setup time when $\overline{\text{CLK}}$ is switched over	250		ns
Input data hold time	t _h	Input data hold time when CLK is switched over	250		ns

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Note 4: $C_L = 100 \text{ pF}, R_L = 1 \text{ k}\Omega$

E²PROM Characteristics (GND = 0 V, 3.0 V \leq V_{CC} \leq 3.6 V, T_{opr} = -40~85°C)

Characteristics	Symbol	Test Condition	Min	Тур.	Max	Unit
All erase time	t _E		_	6	10	ms
Program time	t _P		_	6	10	ms
Endurance	N _{EW}		1 × 10 ⁵	_	_	Times
Data retention time	t _{RET}		10		_	Year

E²PROM Characteristics (GND = 0 V, 2.7 V \leq V_{CC} \leq 3.6 V, T_{opr} = -40~85°C)

Characteristics	Symbol	Test Condition	Min	Тур.	Max	Unit
All erase time	t _E		_	7	13	ms
Program time	t _P		_	7	13	ms
Endurance	N _{EW}		1 × 10 ⁵	_	_	Times
Data retention time	t _{RET}		10	_	_	Year

Capacitance Characteristics (Ta = 25°C)

Characteristics	Symbol	Test Condition	V _{CC} (V)	Тур.	Unit
Input capacitance	C _{IN}		3.3	4	pF
Output capacitance	CO		3.3	3	pF
Equivalent Internal capacitance	C _{PD}	f _{IN} = 1 MHz (Note	5) 3.3	8.5	pF

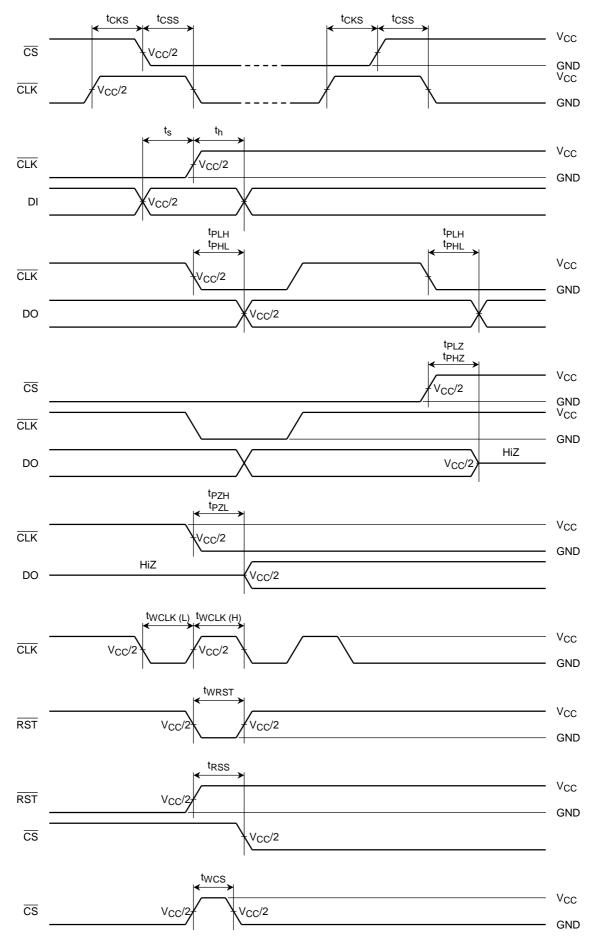
Note 5: C_{PD} denotes the IC's internal equivalent capacitance calculated from the amount of current it consumes while operating.

The average current consumption during non-loaded operation is obtained from the equations below.

 $I_{CC (Read)} = f_{CLK} \cdot C_{PD} \cdot V_{CC} + I_{CC1} + I_{CC2} \cdot 3.5/24$

ICC (Prog) = fCLK·CPD·VCC + ICC1 + ICC3

A.C. Characteristics Timing Chart

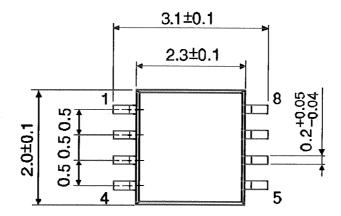


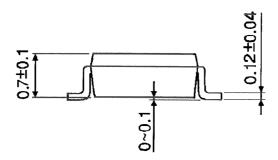
Input/Output Circuits of Pins

Pin Name	Туре	Input/Output Circuit	Remarks
CS DI RST	Input		
CLK	Input		Hysteresis input
DO	Output	Output control signal V _{CC}	Initial "HiZ"

Package Dimensions

SSOP8-P-0.50A Unit: mm





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Weight: 0.01 g (typ.)

RESTRICTIONS ON PRODUCT USE

000707EBA

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